

Notice of References Cited

Application/Control No.

10/591,433

Applicant(s)/Patent Under
Reexamination
IZUMI ET AL.

Examiner

DWIN M. CRAIG

Art Unit

2123

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.